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November 2005

FDS4897C

Dual N & P-Channel PowerTrench® MOSFET

General Description

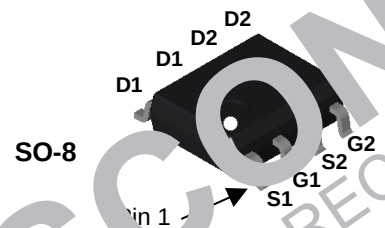
These dual N- and P-Channel enhancement mode power field effect transistors are produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize on-state resistance and yet maintain superior switching performance.

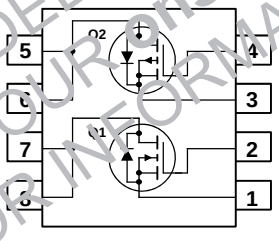
Application

- Inverter
- Power Supplies

Features

- **Q1**: N-Channel
  6.2A, 40V $R_{DS(on)}$ = 29mΩ @ V_{GS} = 10V
  $R_{DS(on)}$ = 36mΩ @ V_{GS} = 4.5V
- **Q2**: P-Channel
  –4.4A, –40V $R_{DS(on)}$ = 56mΩ @ V_{GS} = –10V
  $R_{DS(on)}$ = 90mΩ @ V_{GS} = –4.5V
- High power handling capability in a widely used surface mount package
- RoHS compliant





Absolute Maximum Ratings

T_A = 25°C unless otherwise noted

Symbol	Parameter		Q1	Q2	Units
V_{DSS}	Drain-Source Voltage		40	40	V
V_{GSS}	Gate-Source Voltage		±20	±20	V
I_D	Drain Current - Continuous	(Note 1a)	6.2	–4.4	A
	- Pulsed		20	–20	
P_D	Power Dissipation for Dual Operation		2		W
	Power Dissipation for Single Operation	(Note 1a)	1.6		
		(Note 1b)	1		
		(Note 1c)	0.9		
T_J, T_{STG}	Operating and Storage Junction Temperature Range		–55 to +150		°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	40	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDS4897C	FDS4897C	13"	12mm	2500 units

Electrical Characteristics

T_A = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Type	Min	Typ	Max	Units
Drain-Source Avalanche Ratings (Note 3)							
E_{AS}	Drain-Source Avalanche Energy (Single Pulse)	V_{DD} = 40 V, I_D = 7.3 A, L = 1 mH	Q1			27	mJ
		V_{DD} = –40 V, I_D = –8.7 A, L = 1 mH	Q2			38	mJ
I_{AS}	Drain-Source Avalanche Current		Q1 Q2		7.3 –8.7		A
Off Characteristics							
BV_{DSS}	Drain-Source Breakdown Voltage	V_{GS} = 0 V, I_D = 250 µA V_{GS} = 0 V, I_D = –250 µA	Q1 Q2	40 –40			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I_D = 250 µA, Referenced to 25°C I_D = –250 µA, Referenced to 25°C	Q1 Q2			–4	mV/°C
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = 32 V, V_{GS} = 0 V V_{DS} = –32 V, V_{GS} = 0 V	Q1 Q2			1 –1	µA
I_{GSS}	Gate-Body Leakage	V_{GS} = ±20 V, V_{DS} = 0 V	All			±100	nA
On Characteristics (Note 2)							
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS} = V_{GS}, I_D = 250 µA V_{DS} = V_{GS}, I_D = –250 µA	Q1 Q2	1 –1	1.9 –1.7	3 –3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I_D = 250 µA, Referenced to 25°C I_D = –250 µA, Referenced to 25°C	Q1 Q2		–5 4		mV/°C
$R_{DS(on)}$	Static Drain-Source On-Resistance	V_{GS} = 10 V, I_D = 6.2 A V_{GS} = 4.5 V, I_D = 4.8 A V_{GS} = 10 V, I_D = 6.2 A, T_J = 125°C	Q1		21 26 29	28 36 43	mΩ
		V_{GS} = –10 V, I_D = –4.4 A V_{GS} = –4.5 V, I_D = –3.8 A V_{GS} = –10 V, I_D = –4.4 A, T_J = 125°C	Q2		37 50 55	46 63 73	
g_{FS}	Forward Transconductance	V_{DS} = 10 V, I_D = 6.2 A V_{DS} = –10 V, I_D = –4.4 A	Q1 Q2		21 12		S
Dynamic Characteristics							
C_{iss}	Input Capacitance	V_{DS} = 20 V, V_{GS} = 0 V, f = 1.0 MHz	Q1 Q2		760 1050		pF
C_{oss}	Output Capacitance	V_{DS} = –20 V, V_{GS} = 0 V, f = 1.0 MHz	Q1 Q2		100 140		pF
C_{rss}	Reverse Transfer Capacitance		Q1 Q2		60 70		pF
R_G	Gate Resistance	f = 1.0 MHz	Q1 Q2		1.2 9		Ω

Electrical Characteristics (continued)

T_A = 25°C unless otherwise noted

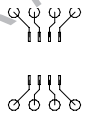
Symbol	Parameter	Test Conditions	Type	Min	Typ	Max	Units
Switching Characteristics (Note 2)							
$t_{d(on)}$	Turn-On Delay Time	Q1 V_{DD} = 20 V, I_D = 1 A,	Q1 Q2		9 12	18 22	ns
t_r	Turn-On Rise Time	V_{GS} = 10V, R_{GEN} = 6 Ω	Q1 Q2		5 15	10 27	ns
$t_{d(off)}$	Turn-Off Delay Time	Q2 V_{DD} = –20 V, I_D = –1 A,	Q1 Q2		23 45	37 72	ns
t_f	Turn-Off Fall Time	V_{GS} = –10V, R_{GEN} = 6 Ω	Q1 Q2		3 18	6	ns
Q_g	Total Gate Charge	Q1 V_{DS} = 20 V, I_D = 6.2 A, V_{GS} = 10 V	Q1 Q2			20 28	nC
Q_{gs}	Gate-Source Charge	Q2	Q1 Q2		2.4 3		nC
Q_{gd}	Gate-Drain Charge	V_{DS} = –20 V, I_D = –4.4 A, V_{GS} = –10 V	Q1 Q2		2. 4		nC
Drain–Source Diode Characteristics							
V_{SD}	Drain-Source Diode Forward Voltage	V_{GS} = 0 V, I_S = 1.3 A (Note V_{GS} = 0 V, I_S = –1.3 (N	Q2		0.7 –0.7	1.2 –1.2	V
t_{rr}	Diode Reverse Recovery Time	Q1 I_F = 6.2 A, = 100 /µs	Q1 Q2		17 24		ns
Q_{rr}	Diode Reverse Recovery Charge	Q2 I_F = –4. A, d_{iF}/d_t 100 A/µs	Q1 Q2		7 12		nC

Notes:

1. $R_{\theta JA}$ is the sum of the junction-to-case and c bien hermal nce when the case thermal reference is defined the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by des while R_{θ} s de mined by the use board design

a) °C/W wh nted 0.5 of 2 oz copper

b) 1 °C/W when mounted on a .02 in² pad of 2 oz copper



c) 135°C/W when mounted on a minimum pad.

Scale 1 on le r size pape

Pul est: Pulse Width < 300µs, Duty Cycle < 2.0%

3. EAS(avalanche, Single-Pulse ra ing) is guaranteed by design if device is operated within the UIS SOA boundary of the device.

Typical Characteristics: Q1 (N-Channel)

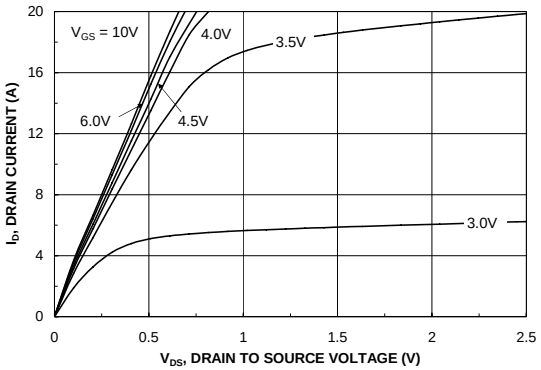


Figure 1. On-Region Characteristics.

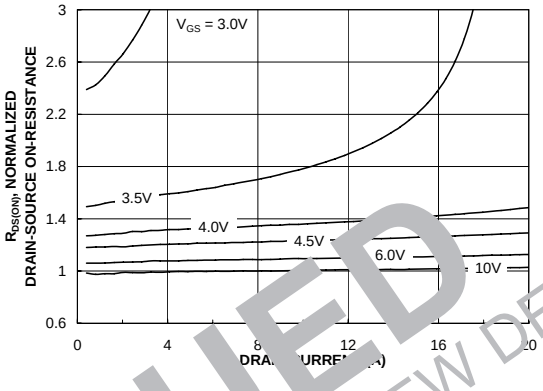


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

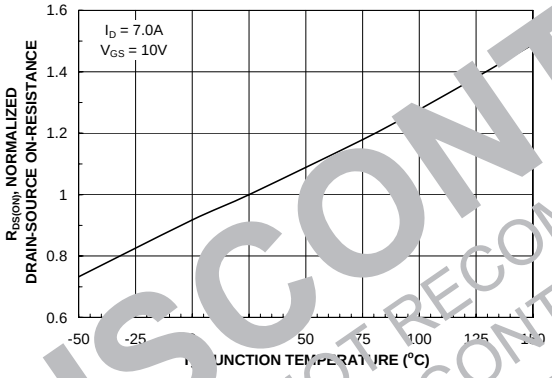


Figure 3. On-Resistance Variation with Temperature.

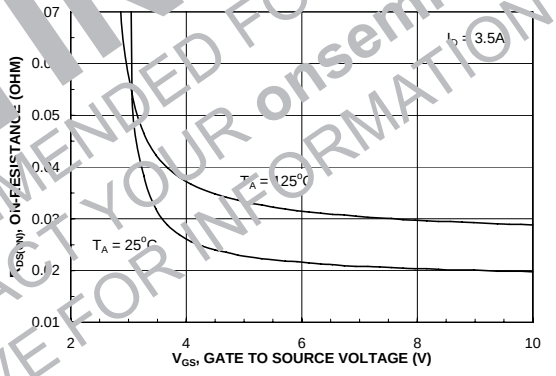


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

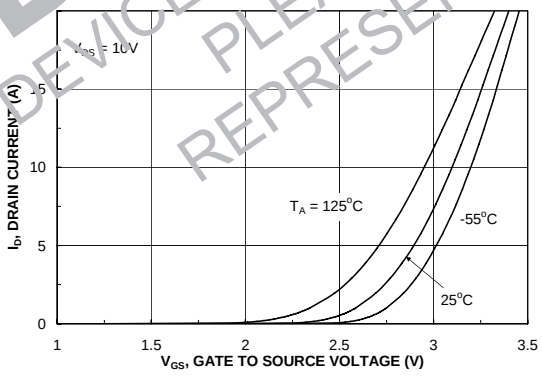


Figure 5. Transfer Characteristics.

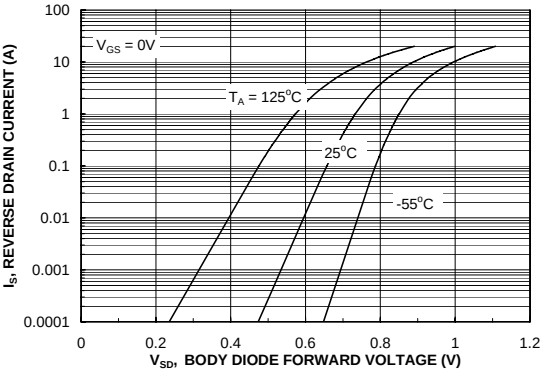


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics: Q1 (N-Channel)

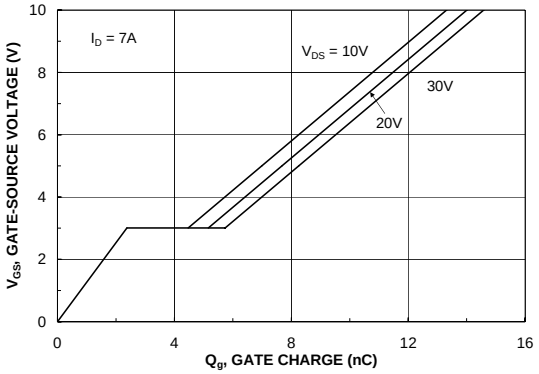


Figure 7. Gate Charge Characteristics.

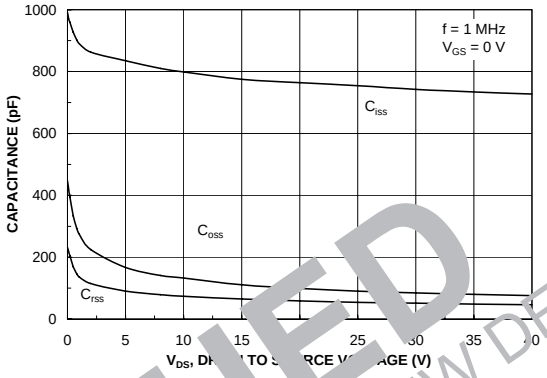


Figure 8. Capacitance Characteristics.

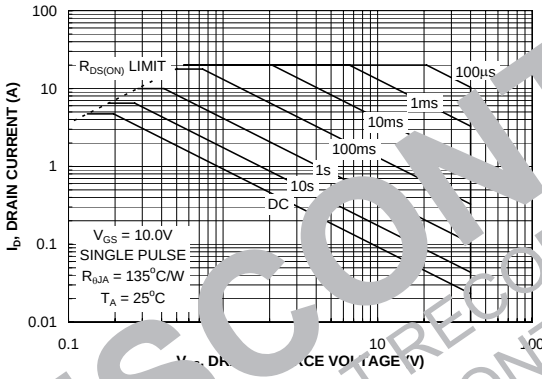


Figure 9. Maximum Safe Operating Area.

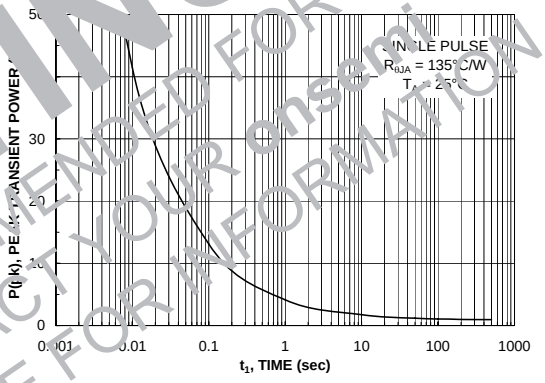


Figure 10. Single Pulse Maximum Power Dissipation.

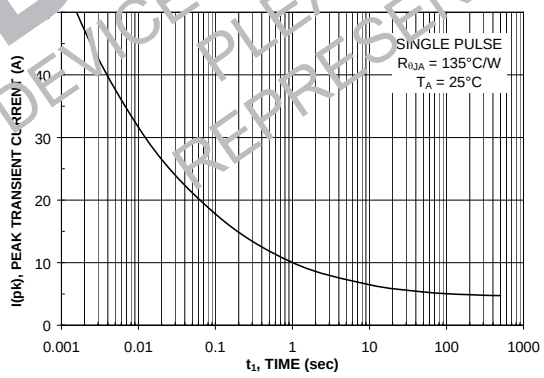


Figure 11. Single Pulse Maximum Peak Current.

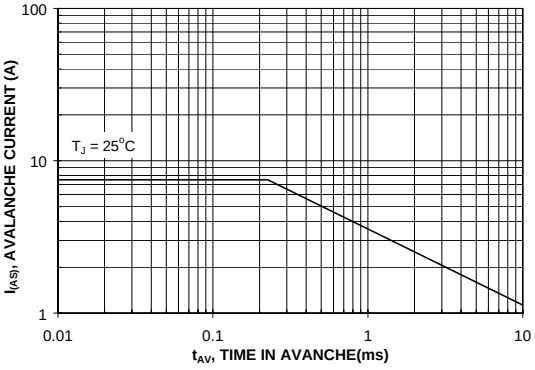


Figure 12. Unclamped Inductive Switching Capability.

Typical Characteristics: Q2 (P-Channel)

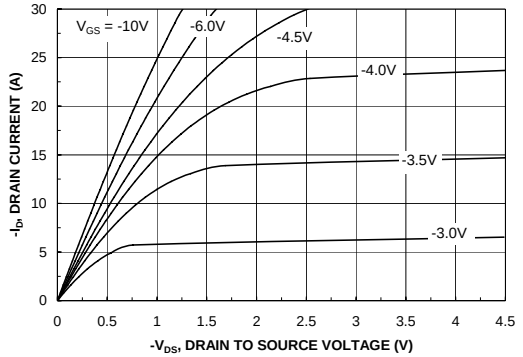
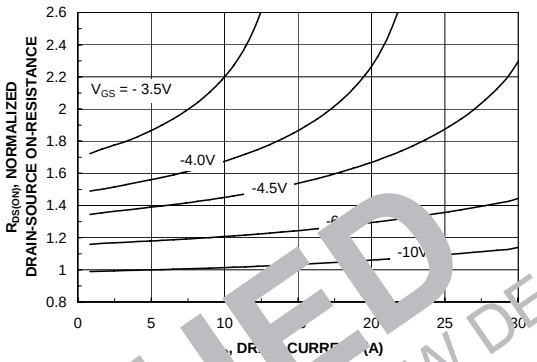


Figure 13. On-Region Characteristics.



Figu 14. n-Res stance Va iation with Dr n C rer and Gate Voltage.

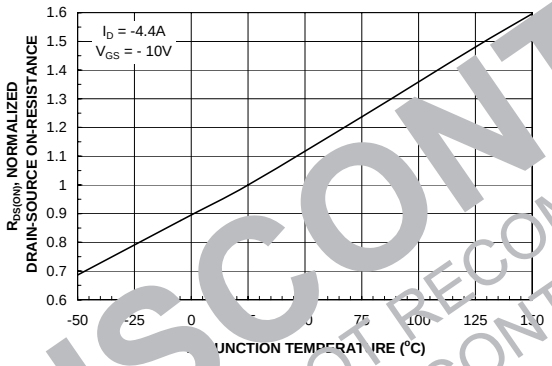


Fig e 15. On-Resistance Va iation with Temperature

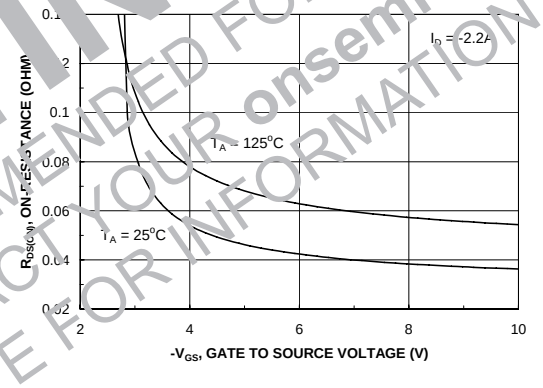


Figure 16. On-Resistance Variation with Gate-to-Source Voltage.

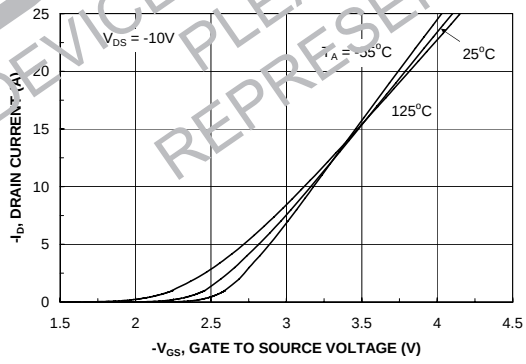


Figure 17. Transfer Characteristics.

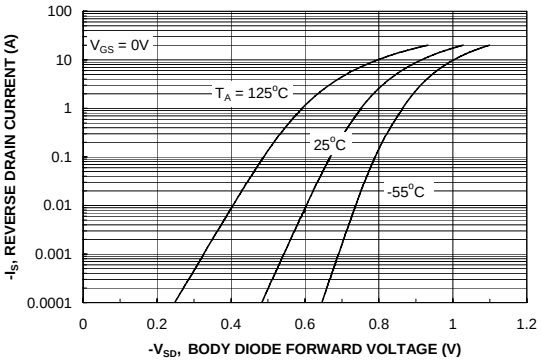


Figure 18. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics: Q2 (P-Channel)

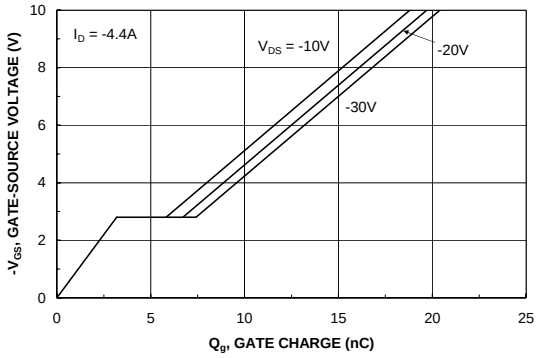


Figure 19. Gate Charge Characteristics.

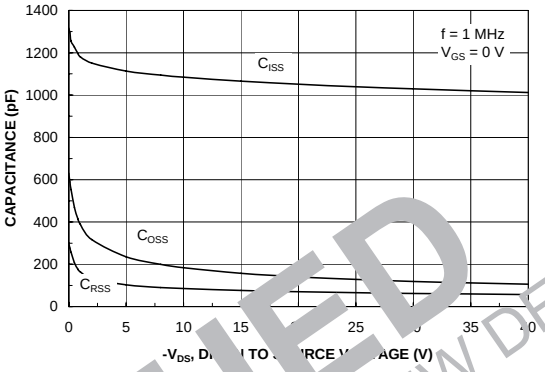


Figure 20. Capacitance Characteristics.

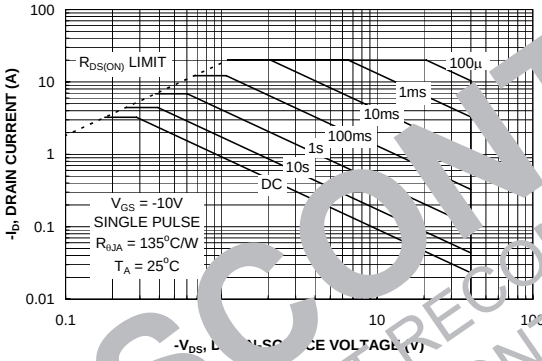


Figure 21. Maximum Safe Operating Area.

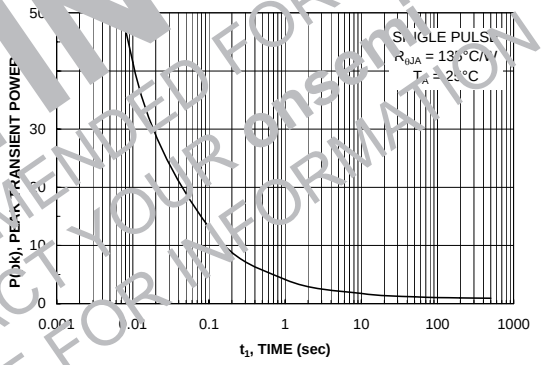


Figure 22. Single Pulse Maximum Power Dissipation.

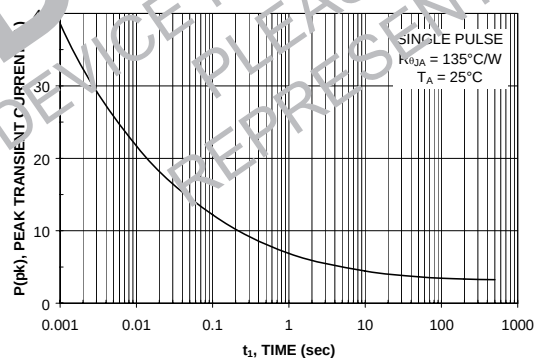


Figure 23. Single Pulse Maximum Peak Current

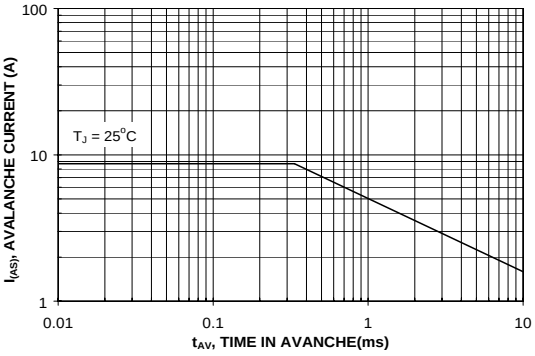


Figure 24. Unclamped Inductive Switching Capability

Typical Characteristics : N and P-Channel

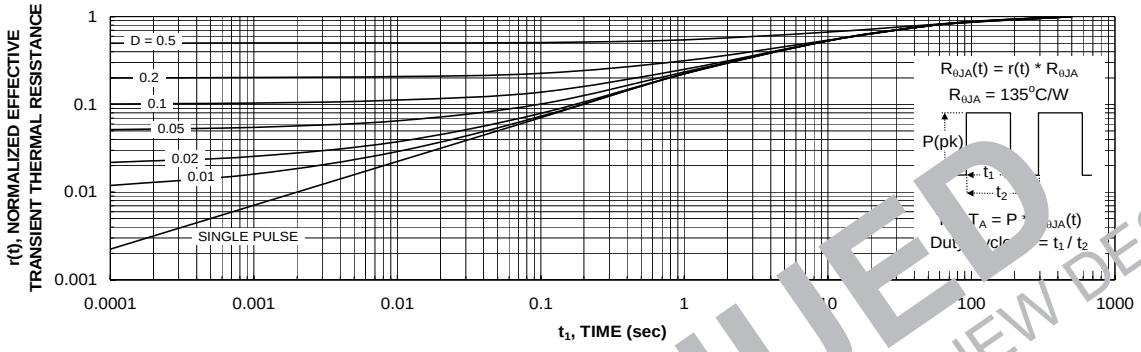


Figure 25. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c.
Transient thermal response will change depending on the circuit board design.

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2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

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Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.

Rev. I17

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